

# Fabrication

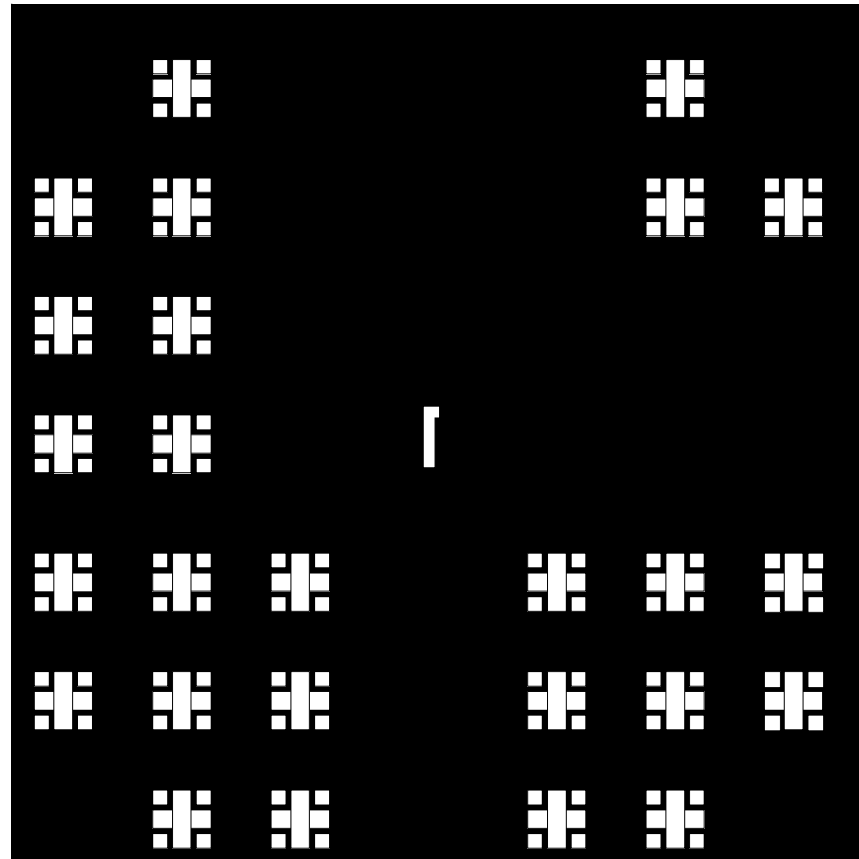
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- “Top down” approach to nanotechnology
- This is overview, for more details take MAE courses by Marc Madou, Andre Shkel
- Thanks to Sungmu Kang for INRF images

# Photomasks

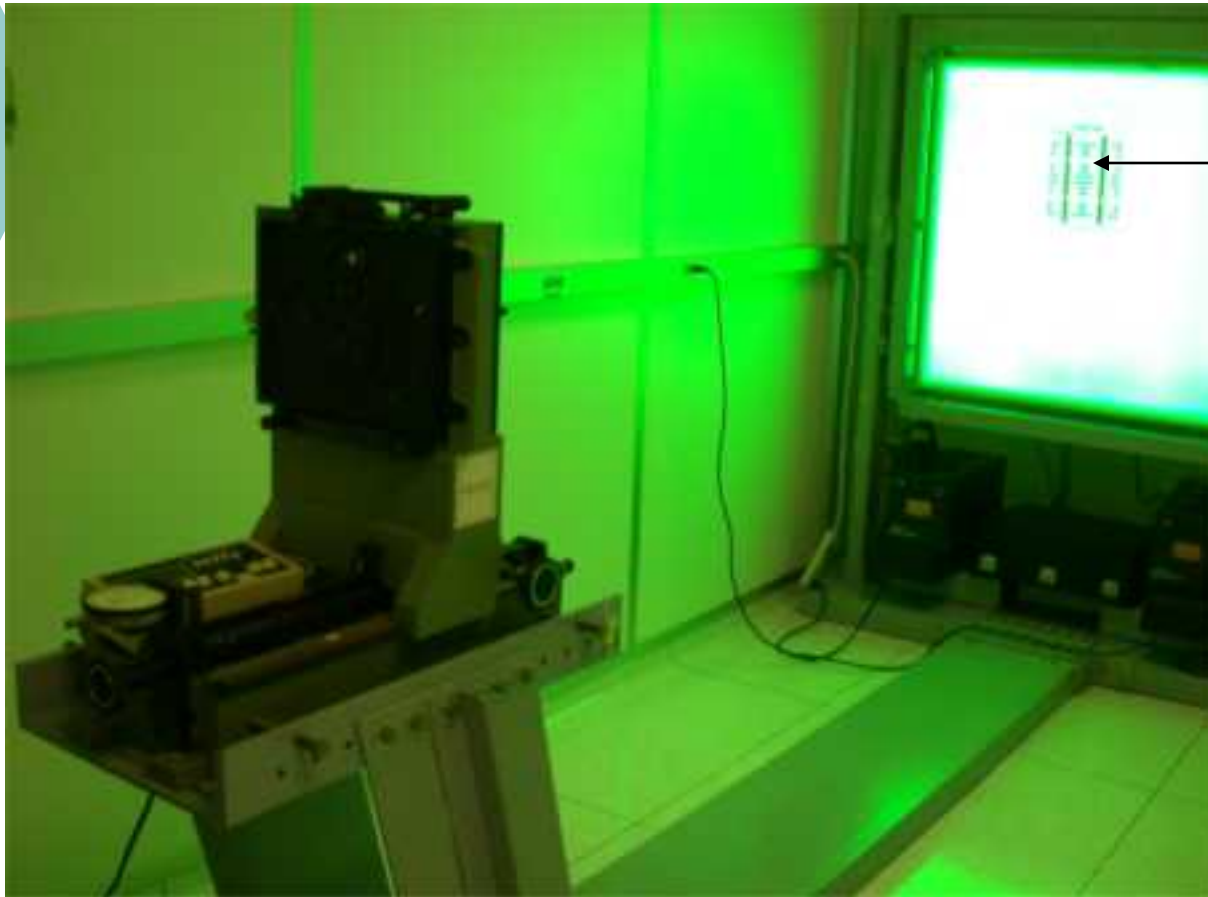
Design geometry on computer.

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# Mask fabrication

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← transparency

After Exposure  
Developer  
Stop bath  
Fixer

Dark room (1/20 reduction)

# Spin on photoresist

wafer

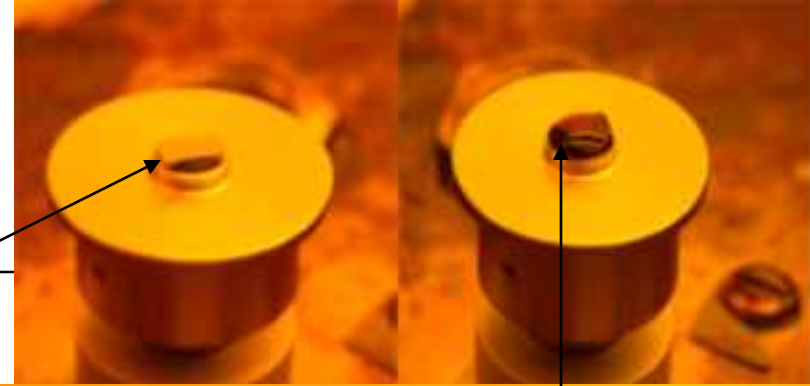
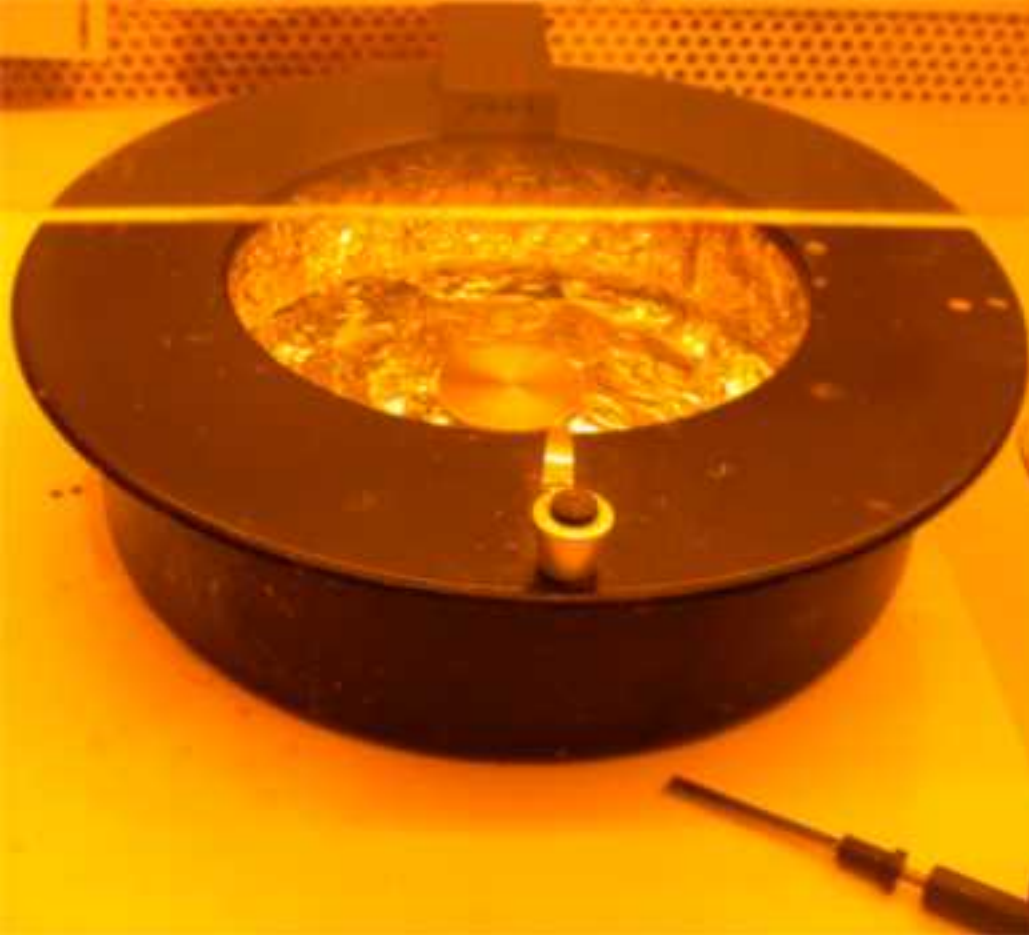


Photo resist



## Photo resist spinner

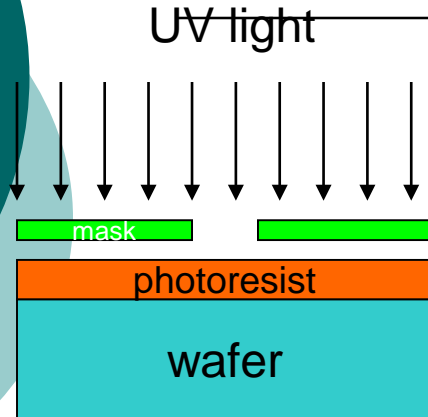
# Soft bake

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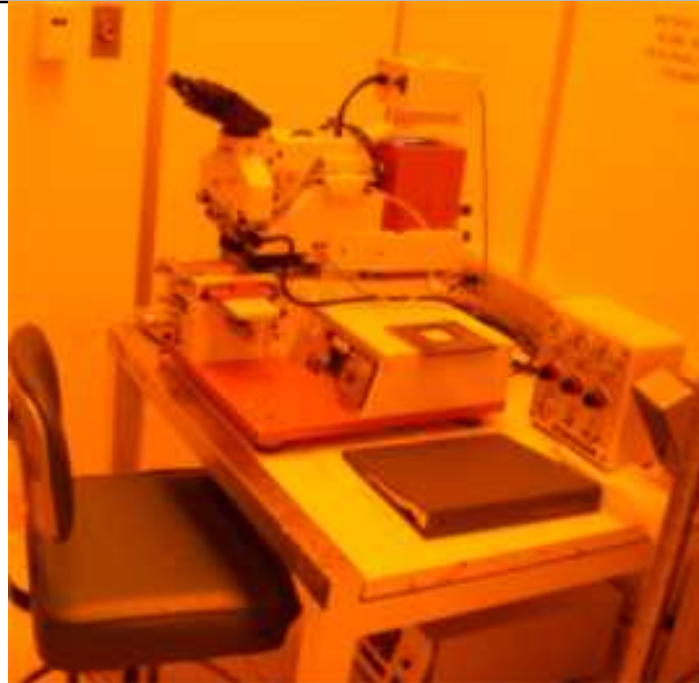


Oven for soft baking of photo resist  
(at 90C for 30 min)

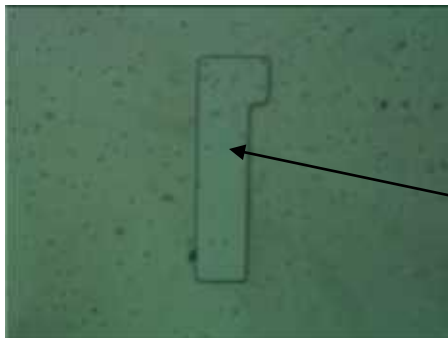
# Expose to UV light



Development  
For Shipley 1827  
Water : MF351 = 5.5 : 1



Mask Aligner



Exposed regions  
dissolved in developer  
leaving bare wafer

*This is the step which limits  
the spatial resolution.*

# Thermal evaporation



Thermo evaporator



Alumina coated W boat

Useful for e.g.  
Al, Ni, Au, Cr, Ti, NiCr, Pb, Sn

# E-beam evaporation



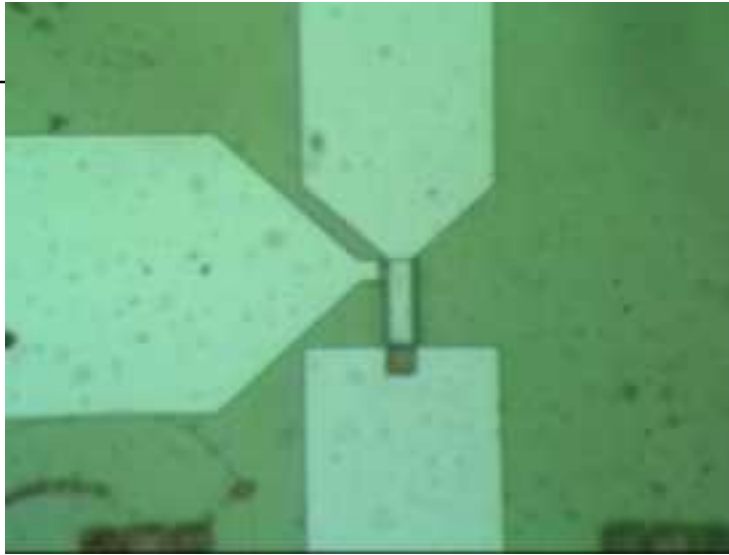
Electron beam evaporator

Au

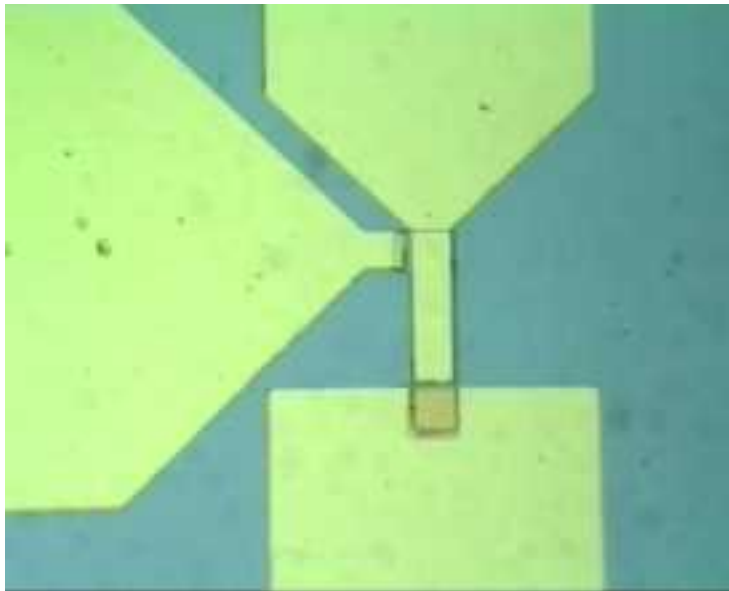




# Liftoff



Opening of photo resist  
for Ti/Au gate



After deposition of Ti/Au,  
then soaking in acetone

# Resolution of optical lithography

$$R = \frac{3}{2} \sqrt{\frac{\lambda z}{2}}$$

Contact printing

z is resist thickness  
(typically 0.1-1  $\mu\text{m}$ )

$$R = 0.61 \frac{\lambda}{NA}$$

Projection printing

NA is numerical aperture  
(typically 0.5)

# Light sources

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Source	$\lambda$	Resolution
○ Hg lamp	(g-line) 436 nm	400 nm
○ Hg lamp	(i-line) 365 nm	350 nm
○ KrF	248 nm	150 nm
○ ArF	193 nm	80 nm
○ F <sub>2</sub>	157 nm	research

↑ increasing cost

Extreme UV, x-ray lithography research topics.  
Difficulties lie in sources, and materials for optics and masks.

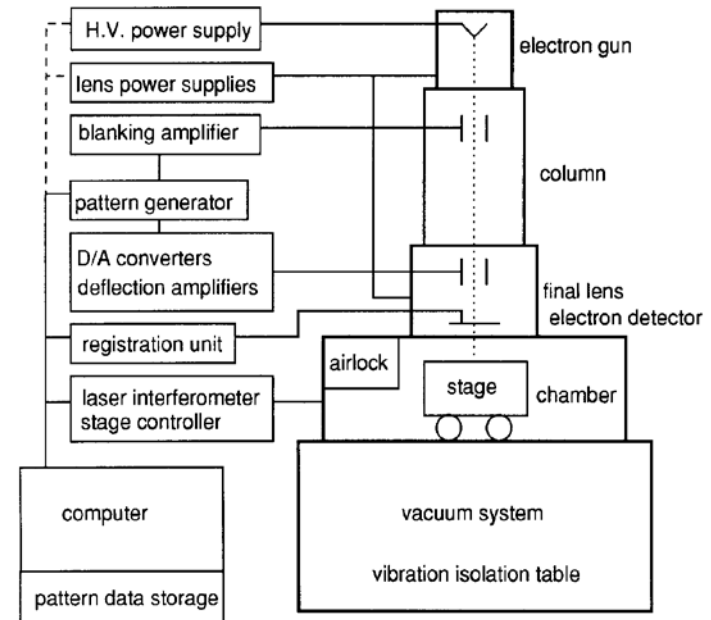
# Electron Beam Lithography

## Advantages

- Resolution
  - electron wavelength small
  - beamsize 1 nm
  - resolution from scattering typically 10 nm
- Flexibility
  - All patterns under computer control

## ○ Disadvantages

- Cost
  - Need high vacuum
  - Need precision electron focusing magnets
- Throughput
  - Only one pixel exposed at a time
  - Not commercially viable except for a few applications




Reference: SPIE Handbook of Microlithography, Micromachining, and Microfabrication available at <http://www.cnf.cornell.edu/spiebook/toc.htm>


*In spite of its disadvantages, e-beam lithography is the main tool for nanotechnology research.*

 Integrated Nanosystems Research Facility  
Engineering the nanoworld at the University of California, Irvine



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Acc.V Spot Magn Det WD  20  $\mu$ m  
5.00 kV 3.0 800x SE 7.2 XL30 SFEG D1591

Irvinne

Acc.V Spot Magn Det WD Exp |-----| 500 nm  
30.0 kV 3.0 64000x SE 7.1 0 XL30 SFEG D1591

34.6 nm

21. nm

24. nm

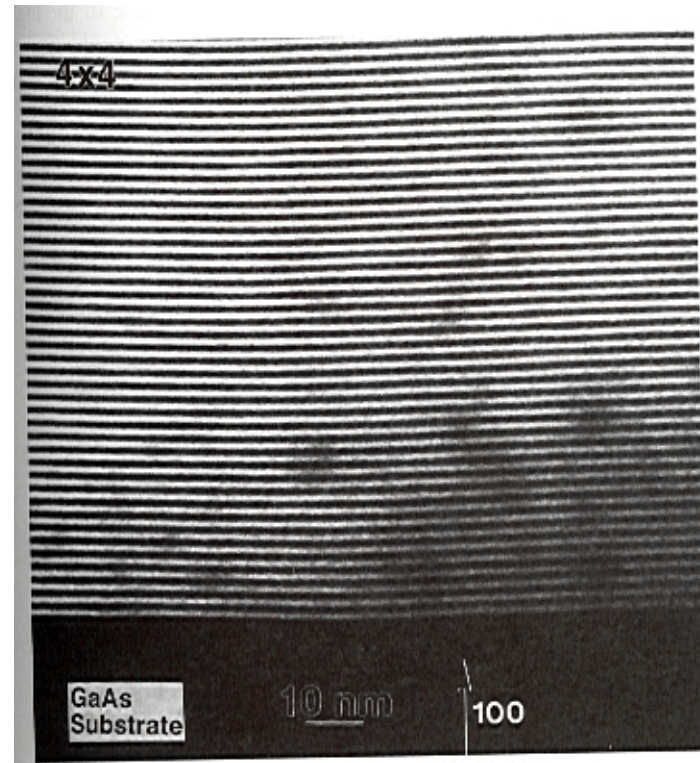
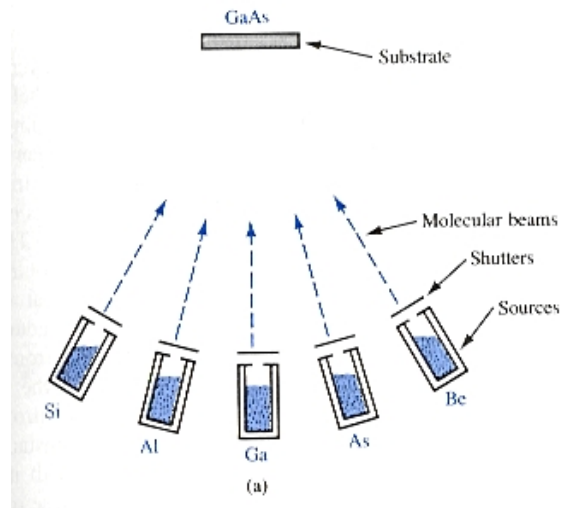
45.1 nm

25.6 nm

27.1 nm

Acc.V	Spot	Magn	Det	WD	200 nm
30.0 kV	3.0	128000x	SE	7.1	XL30 SFEG D1591

# Molecular Beam Epitaxy (MBE)



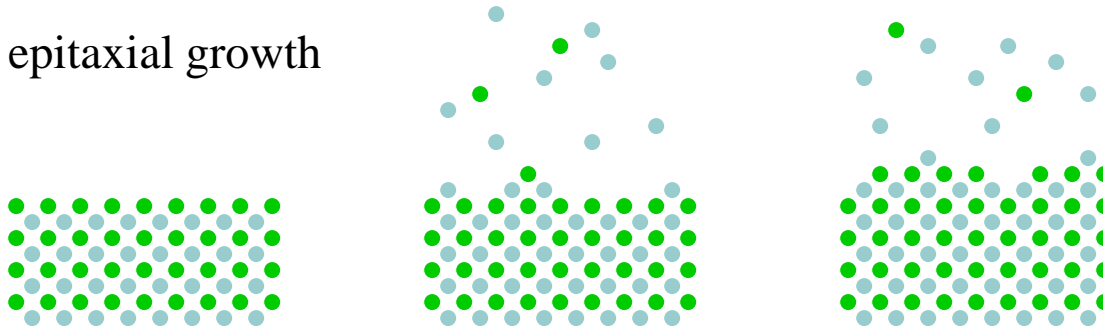
4 atom per layer!

(From Streetman, Solid State Electronic Devices)



# MBE

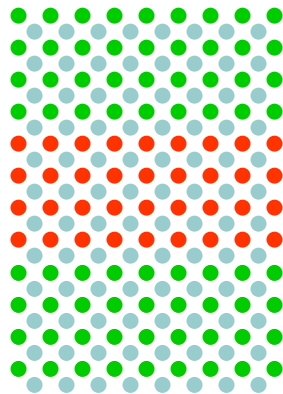
epitaxial growth



AlAs

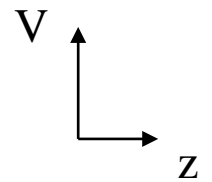
GaAs

AlAs



2.2 eV

1.4 eV



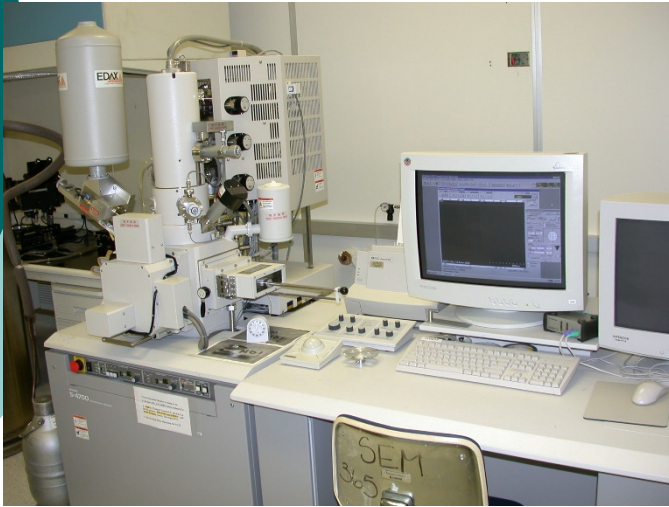
Also InP, InGaAs, InAlAs, InGaAsP ...

# Characterization

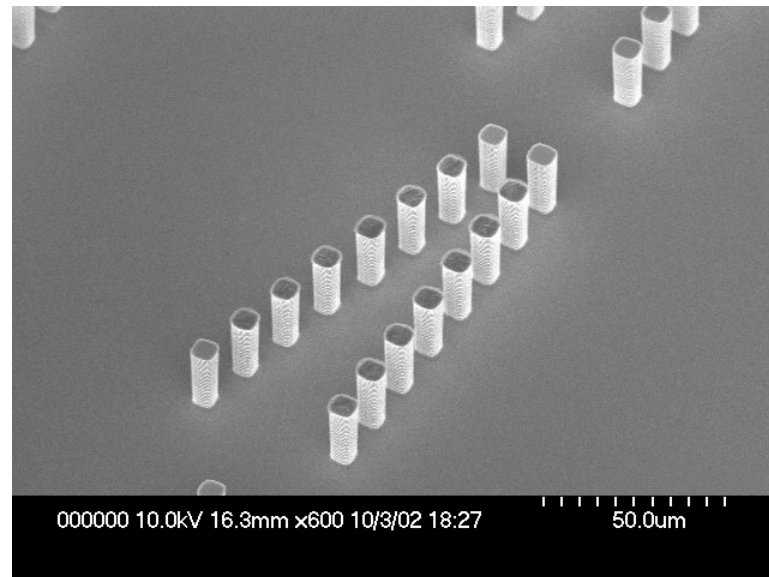
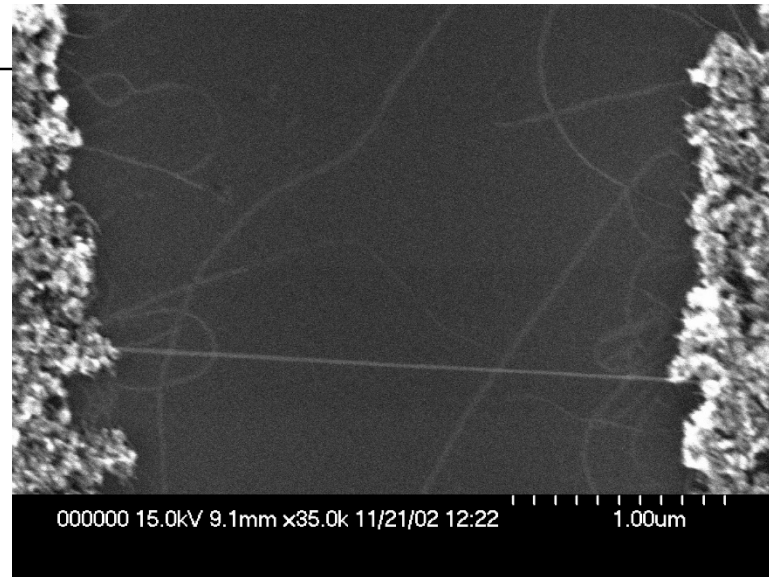
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- Optical microscopy cannot see better than wavelength of light,  $\sim 1 \mu\text{m}$
- Scanning electron microscope (SEM)
- Transmission electron microscope (TEM)
- Scanning probe microscopy (SPM)
- Atomic force microscope (AFM)

# SEM

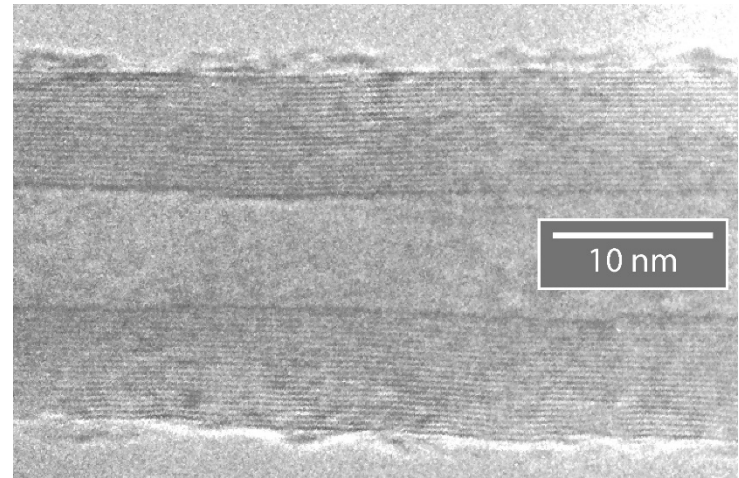


- Advantages:
  - resolution to 1 nm
  - fast
  - 3d structures visible
  - back-scattered x-ray spectrum gives compositional information
- Disadvantage
  - must be in vacuum environment (not good for bio)
  - expensive
  - samples must be conductive





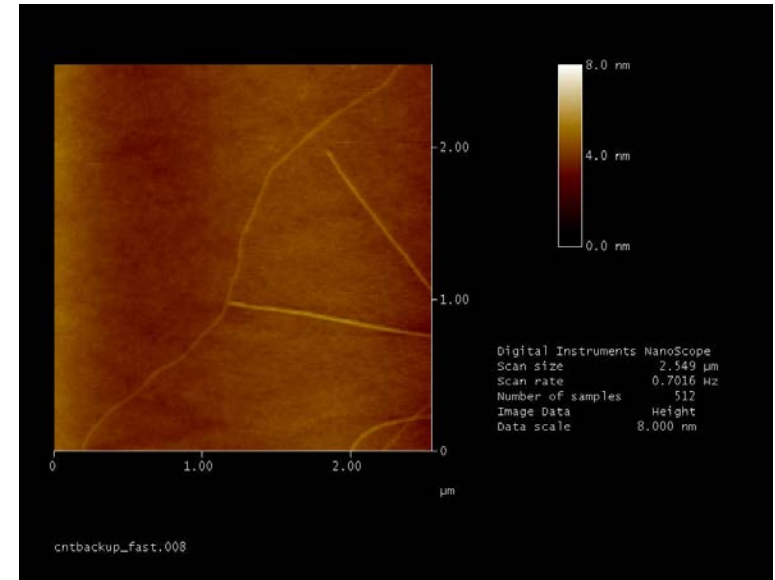
## Multiwalled carbon nanotube



Shengdong Li, submitted

- Advantages
  - resolution < 1 nm
  - fast
  - diffraction pattern gives crystallographic info
- Disadvantages
  - expensive
  - high vacuum
  - sample must be thinned

# SPM/AFM



- Mode of operation
  - non-contact
  - tunneling
- Advantages
  - works in air or liquid
  - angstrom resolution possible
  - can image individual atoms
  - probes various quantities
    - conductance
    - magnetism
- Disadvantages
  - extremely slow
  - many minutes for one image

# Length scales

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- Atoms
  - ~ angstrom  $10^{-10}$  m
- Light
  - wavelength ~  $\mu\text{m}$
- Electrons
  - De Broglie wavelength =  $h/p$  (quantum mechanics)  
=  $\text{sqrt}(150/V)$  in angstroms ( $V$  is energy in volts)  
~0.1-10 nm
  - If circuit element is about the size of an electron wavelength, wave nature will be *crucial*
  - Conductance quantized at these small scales in units of  $e^2/h$
- Mean free path (MFP)
  - $10^{-10}$  m in metals at room temperature
  - $10^{-4}$  m in ultra high quality semiconductors at low temperatures

# Energies

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- Electronic transition energies
  - ~ 1-10 eV
- Fermi energy
  - 1-10 eV in metals
  - 1-10 meV in semiconductors
- $kT$ 
  - 30 meV at room temperature